

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 203524US2PCT		SERIAL NO. 09/786,161	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Miroslaw Z. BOBER			
				FILING DATE March 2, 2001		GROUP 2621	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
✓	AN	6-309465	11/04/94	JAPAN		X	
✓	AO	10-55447 /	02/24/98	JAPAN		X	
✓	AP	2 203 877 ✓	10/26/88	GREAT BRITAIN			
✓	AQ	0 281 725 ✓	09/14/88	EUROPE			
✓	AR	WO 88/02158 ✓	03/24/88	WIPO			
	AS						
	AT						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
✓	AU	F. MOKHTARIAN, et al., Lecture Notes in Computer Science, Vol. 1311, Pages 140-147, "A NEW APPROACH TO COMPUTATION OF CURVATURE SCALE SPACE IMAGE FOR SHAPE SIMILARITY RETRIEVAL", 1997					
✓	AV	S. ABBASI, et al., Lecture Notes in Computers Science, Vol. 1252, Pages 284-295, "RELIABLE CLASSIFICATION OF CHRYSANTHEMUM LEAVES THROUGH CURVATURE SCALE SPACE", 1997					
✓	AW	F. MOKHTARIAN, et al., Machine Intelligence, Vol. 14, No. 8, Pages 789-805, "A THEORY OF MULTISCALE, CURVATURE-BASED SHAPE REPRESENTATION FOR PLANAR CURVES", August 1, 1992					
✓	AX	N. KATZIR, et al., Proceedings of the International Conference on Pattern Recognition, Vol. Conf., No. 10, Pages 842-846, "PLANAR CURVE SEGMENTATION FOR RECOGNITION OF PARTIALLY OCCLUDED SHAPES", 1990					
✓	AY	D. T. NGUYEN, et al., 8049E I.E.E. Proceedings-E/Computers and Digital Techniques, Vol. 135, No. 6, Part E., Pages 307-311, "SCALE BASED ALGORITHM FOR RECOGNITION OF BLURRED PLANAR OBJECTS", November 1, 1988					
✓	AZ	B. GUENSEL, et al., Patern Recognition, Vol. 31, No. 7, Pages 931-944, "SHAPE SIMILARITY MATCHING FOR QUERY-BY-EXAMPLE", July 1, 1998					
Examiner					Date Considered 1.9.04		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.